Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/600,560	KIM ET AL.
Examiner	Art Unit
Andrew L. Nalven	2134

	SEAR	CHED	
Class	Subclass	Date	Examiner
380	28	11/8/2006	ALN
380	30	11/8/2006	ALN
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	INTERFERENCE SEARCHED			
	Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR)
	DATE	EXMR
East Keyword Search	11/7/2006	ALN
Inventor Name Search	11/8/2006	ALN
ACM Database Search	11/8/2006	ALN
IEEE Search	11/8/2006	ALN